

STL8N6F7

N-channel 60 V, 0.021 Ω typ., 8 A STripFET[™] F7 Power MOSFET in a PowerFLAT[™] 3.3x3.3 package

Datasheet - preliminary data



Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max	ID
STL8N6F7	60 V	0.025 Ω	8 A

- Among the lowest R_{DS(on)} on the market
- Excellent figure of merit (FoM)
- Low C_{rss}/C_{iss} ratio for EMI immunity
- High avalanche ruggedness

Applications

• Switching applications

Description

This N-channel Power MOSFET utilizes STripFET[™] F7 technology with an enhanced trench gate structure that results in very low onstate resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Table 1: Device summary

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Order code	Marking	Package	Packing	
STL8N6F7	8N6F7	PowerFLAT™ 3.3x3.3	Tape and reel	

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This is preliminary information on a new product now in development or undergoing evaluation. Details are subject to change without notice.

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage	60	V
V _{GS}	Gate-source voltage	± 20	V
ا _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	36	А
Ι _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	22	А
I _{DM} ⁽¹⁾⁽²⁾	Drain current (pulsed)	144	А
ا _D ⁽³⁾	Drain current (continuous) at T _{pcb} = 25 °C	8	А
ا _D ⁽³⁾	Drain current (continuous) at T _{pcb} = 100 °C	5	А
I _{DM} ⁽²⁾⁽³⁾	Drain current (pulsed)	32	А
P _{TOT} ⁽¹⁾	Total dissipation at T_c = 25 °C	60	W
P _{TOT} ⁽³⁾	Total dissipation at T _{pcb} = 25 °C	3	W
T _{stg}	Storage temperature	55 to 150	°C
Tj	Operating junction temperature	-55 to 150	

Notes:

 $^{(1)}\mbox{This}$ value is rated according to $R_{\mbox{thj-c}}.$

⁽²⁾Pulse width limited by safe operating area.

 $^{(3)}\mbox{This}$ value is rated according to $\mbox{R}_{\mbox{thj-pcb}}.$

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb max.	42.8	°C/W
R _{thj-case}	Thermal resistance junction-case max.	2.1	°C/W

Notes:

⁽¹⁾When mounted on FR-4 board of 1 inch², 2oz Cu, t < 10 sec.



2 Electrical characteristics

(T_c = 25 $^{\circ}$ C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0 V	60			V
I _{DSS}	Zero gate voltage drain current	V _{GS} = 0 V V _{DS} = 60 V			1	μA
I _{GSS}	Gate-body leakage current	V_{GS} = 20 V, V_{DS} = 0 V			100	nA
V _{GS(th)}	Gate threshold voltage	V_{DS} = V_{GS} , I_{D} = 250 μ A	2		4	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 4 A		0.021	0.025	Ω

Table 4: On /off states

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Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Uni t
Ciss	Input capacitance		-	450	-	pF
C _{oss}	Output capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0 V	-	210	-	pF
C _{rss}	Reverse transfer capacitance	VGS – O V	-	22	-	pF
Qg	Total gate charge	$V_{DD} = 48 V, I_D = 8 A,$	-	8	-	nC
Q _{gs}	Gate-source charge	V _{GS} = 10 V	-	TBD	-	nC
Q_{gd}	Gate-drain charge	(see Figure 3: "Test circuit for gate charge behavior")	-	TBD	-	nC

Table 6: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Uni t
t _{d(on)}	Turn-on delay time	$V_{DD} = 30 V, I_D = 4 A,$	-	TBD	-	ns
tr	Rise time	$R_{\rm G} = 4.7 \ \Omega, \ V_{\rm GS} = 10 \ V$	-	TBD	-	ns
$t_{d(off)}$	Turn-off delay time	(see Figure 2: "Test circuit for	-	TBD	-	ns
t _f	Fall time	resistive load switching times")	-	TBD	-	ns



Electrical characteristics

	Table 7: Source-drain diode						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit	
V _{SD} ⁽¹⁾	Forward on voltage	I _{SD} = 8 A, V _{GS} = 0 V	-		1.2	V	
t _{rr}	Reverse recovery time	I _D = 8 A, di/dt = 100 A/μs	-	TBD		ns	
Qrr	Reverse recovery charge	V _{DD} = 48 V	-	TBD		nC	
I _{RRM}	Reverse recovery current	(see Figure 4: "Test circuit for inductive load switching and diode recovery times")	-	TBD		A	

Notes:

 $^{(1)}\text{Pulsed:}$ pulse duration = 300 $\mu\text{s},$ duty cycle 1.5%



3 Test circuits







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4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.



4.1 PowerFLAT 3.3x3.3 package information



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			Package information
Та	ble 8: PowerFLAT™ 3.3x3	3.3 package mechanica	al data
Dim		mm	
Dim.	Min.	Тур.	Max.
A	0.70	0.80	0.90
b	0.25	0.30	0.39
С	0.14	0.15	0.20
D	3.10	3.30	3.50
D1	3.05	3.15	3.25
D2	2.15	2.25	2.35
е	0.55	0.65	0.75
E	3.10	3.30	3.50
E1	2.90	3.00	3.10
E2	1.60	1.70	1.80
Н	0.25	0.40	0.55
К	0.65	0.75	0.85
L	030	0.45	0.60
L1	0.05	0.15	0.25
L2			0.5
θ	8°	10°	12°







5 Revision history

Table 9: Document revision history

Date	Revision	Changes
27-Aug-2015	1	First release.



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